

CTE x,y-axis 4-6ppm/°C
(Low CTE glass cloth)

Low warpage

Ultra-thin
excellent moldability

Applications
IC Package

IC substrate CSP (PoP-Bottom, Flip-Chip, Memory, Module, etc.)



LEXCMGX

Laminate

R-G515S* **R-G515E**

Prepreg

R-G510S* **R-G510E**

*Low CTE glass cloth type

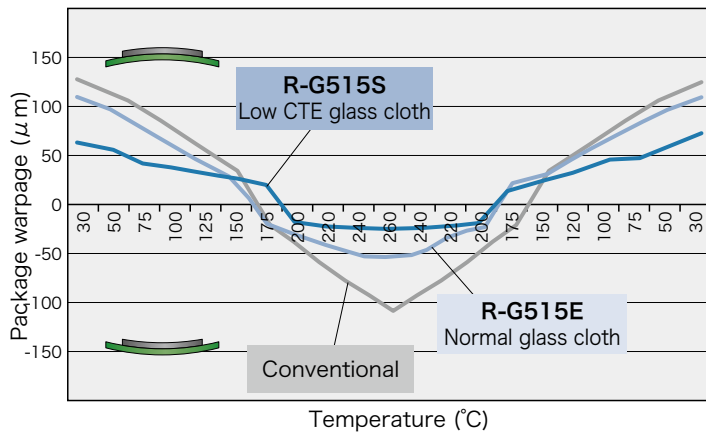
Low CTE ultra-thin IC substrate materials

With an insulation layer thickness of 15 μ m or less, these low-profile materials enable thinner IC package designs. The low CTE reduces warpage and increases reliability.

IC package warpage

R-G515S, with low CTE glass cloth, reduces warpage to about half that of conventional Panasonic materials.

Result



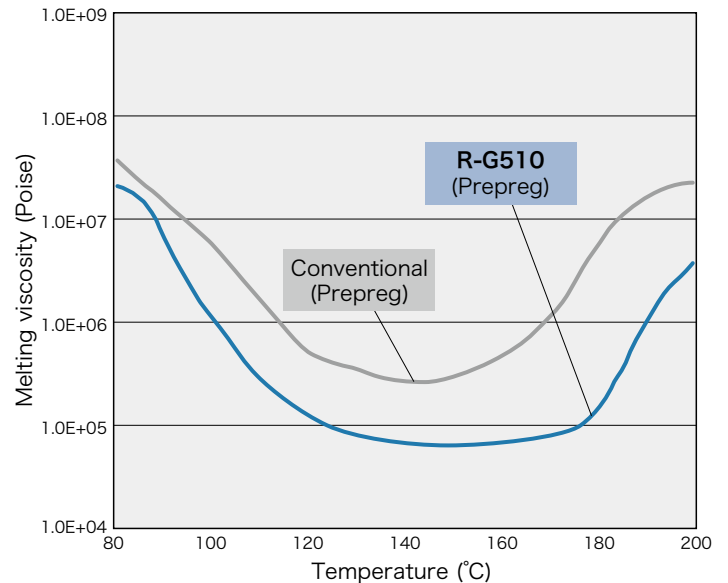
Package construction

Package size	12.5 x 12.5mm
Die size	10 x 10 x 0.10mmt
CUF material	Panasonic CV5300AM
Substrate thickness	0.2mmt (2L Cu:12 μ m)

Melting and curling behavior

R-G510 has a wider melting area and higher moldability than conventional Panasonic materials.

Result



General properties

Item	Test method	Condition	Unit	LEXCMGX R-G515S Low CTE glass cloth	LEXCMGX R-G515E Normal glass cloth	
Glass transition temp.(Tg)	DMA*2	A	°C	220-240	220-240	
CTE x-axis	Internal method	A	ppm/°C	4-6	6-8	
CTE y-axis				4-6	6-8	
Dielectric onstant(Dk)*1	1GHz	IPC-TM-650 2.5.5.9	C-24/23/50	-	4.2	4.4
Dissipation factor(Df)*1					0.008	0.008
Flexural modulus*1	JIS C 6481	25°C	GPa	28	24	

The sample thickness is 0.1mm.
*1 0.8mm *2 Measurement in tensile mode

Please see our website for Notes before you use.